

Automotive-grade dual N-channel 60 V, 0.035 Ω typ., 5 A STripFET™ II Power MOSFET in an SO-8 package

Datasheet - production data

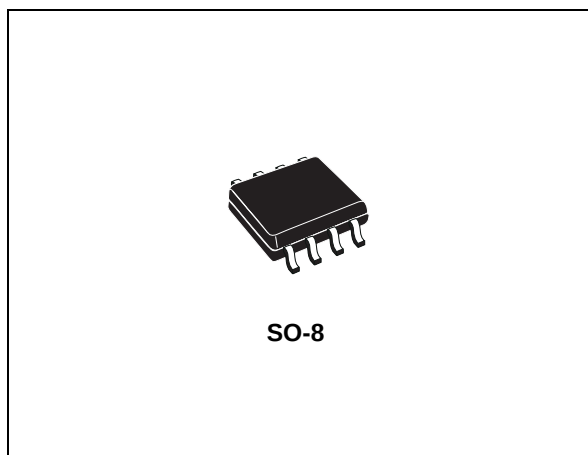
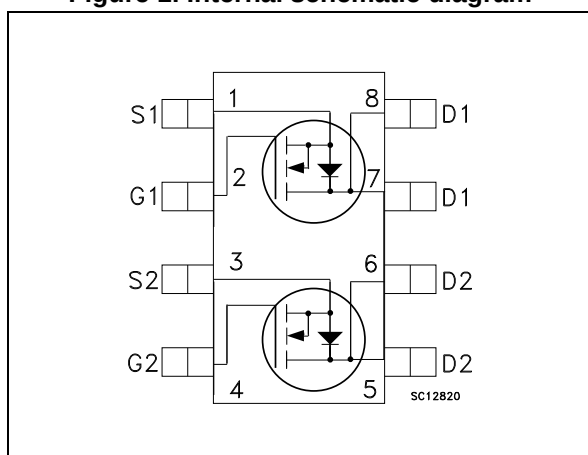


Figure 1. Internal schematic diagram



Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
STS5DNF60L	60 V	0.045 Ω	5 A

- AEC-Q101 qualified
- Low threshold drive



Applications

- Switching applications

Description

This Power MOSFET has been developed using the STripFET process, which is specifically designed to minimize input capacitance and gate charge. This renders the device suitable for use as primary switch in advanced high-efficiency isolated DC-DC converters for telecom and computer applications, and applications with low gate charge driving requirements.

Table 1. Device summary

Order code	Marking	Package	Packing
STS5DNF60L	5DF60L	SO-8	Tape and reel

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	60	V
V_{GS}	Gate- source voltage	± 15	V
I_D	Drain current (continuous) at $T_{pcb} = 25\text{ }^{\circ}\text{C}$	5	A
I_D	Drain current (continuous) at $T_{pcb} = 100\text{ }^{\circ}\text{C}$	3	A
$I_{DM}^{(1)}$	Drain current (pulsed)	16	A
$P_{TOT}^{(2)}$	Total dissipation at $T_{pcb} = 25\text{ }^{\circ}\text{C}$	2	W
T_j	Operating junction temperature range	-55 to 150	$^{\circ}\text{C}$
T_{stg}	Storage temperature range		

1. Pulse width limited by safe operating area

2. $P_{TOT} = 1.6\text{ W}$ for single operation

Table 3. Thermal data

Simbol	Parameter	Value	Unit
$R_{thj-pcb}$	Thermal resistance junction-pcb ⁽¹⁾	62.5	$^{\circ}\text{C/W}$

1. When mounted on 1 inch² FR-4 board, 2 Oz Cu, $t \leq 10\text{ s}$, dual operation

2 Electrical characteristics

($T_{CASE} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 250\text{ }\mu\text{A}$, $V_{GS} = 0\text{ V}$	60			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0\text{ V}$, $V_{DS} = 60\text{ V}$			1	μA
		$V_{GS} = 0\text{ V}$, $V_{DS} = 60\text{ V}$ $T_C = 125\text{ }^{\circ}\text{C}$ ⁽¹⁾			10	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0\text{ V}$, $V_{GS} = \pm 15\text{ V}$			± 100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	1	1.7	2.5	V
$R_{DS(on)}$	Static drain-source on resistance	$V_{GS} = 10\text{ V}$, $I_D = 2\text{ A}$		0.035	0.045	Ω
		$V_{GS} = 4.5\text{ V}$, $I_D = 2\text{ A}$		0.045	0.055	Ω

1. Defined by design, not subject to production test.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
g_{fs}	Forward transconductance	$V_{DS} = 25\text{ V}$, $I_D = 2\text{ A}$	-	25	-	S
C_{iss}	Input capacitance	$V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$	-	1030	-	pF
C_{oss}	Output capacitance			140		pF
C_{rss}	Reverse transfer capacitance			40		pF
Q_g	Total gate charge	$V_{DD} = 48\text{ V}$, $I_D = 4\text{ A}$, $V_{GS} = 4.5\text{ V}$ (see Figure 13)	-	15	-	nC
Q_{gs}	Gate-source charge			4		nC
Q_{gd}	Gate-drain charge			4		nC

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(off)}$	Turn-off delay time	$V_{DD} = 30\text{ V}$, $I_D = 2.2\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$ (see Figure 12 and Figure 17)		15		ns
t_r	Rise time		-	28	-	ns
$t_{d(off)}$	Turn-off delay time			45		ns
t_f	Fall time			10		ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		5	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				16	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 4\text{ A}$, $V_{GS} = 0\text{ V}$	-		1.2	V
t_{rr}	Reverse recovery time	$I_{SD} = 4\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 20\text{ V}$ (see Figure 14)	-	85		ns
Q_{rr}	Reverse recovery charge			85		nC
I_{RRM}	Reverse recovery current			2		A

1. Pulse width limited by safe operating area
2. Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %

2.1 Electrical characteristics (curves)

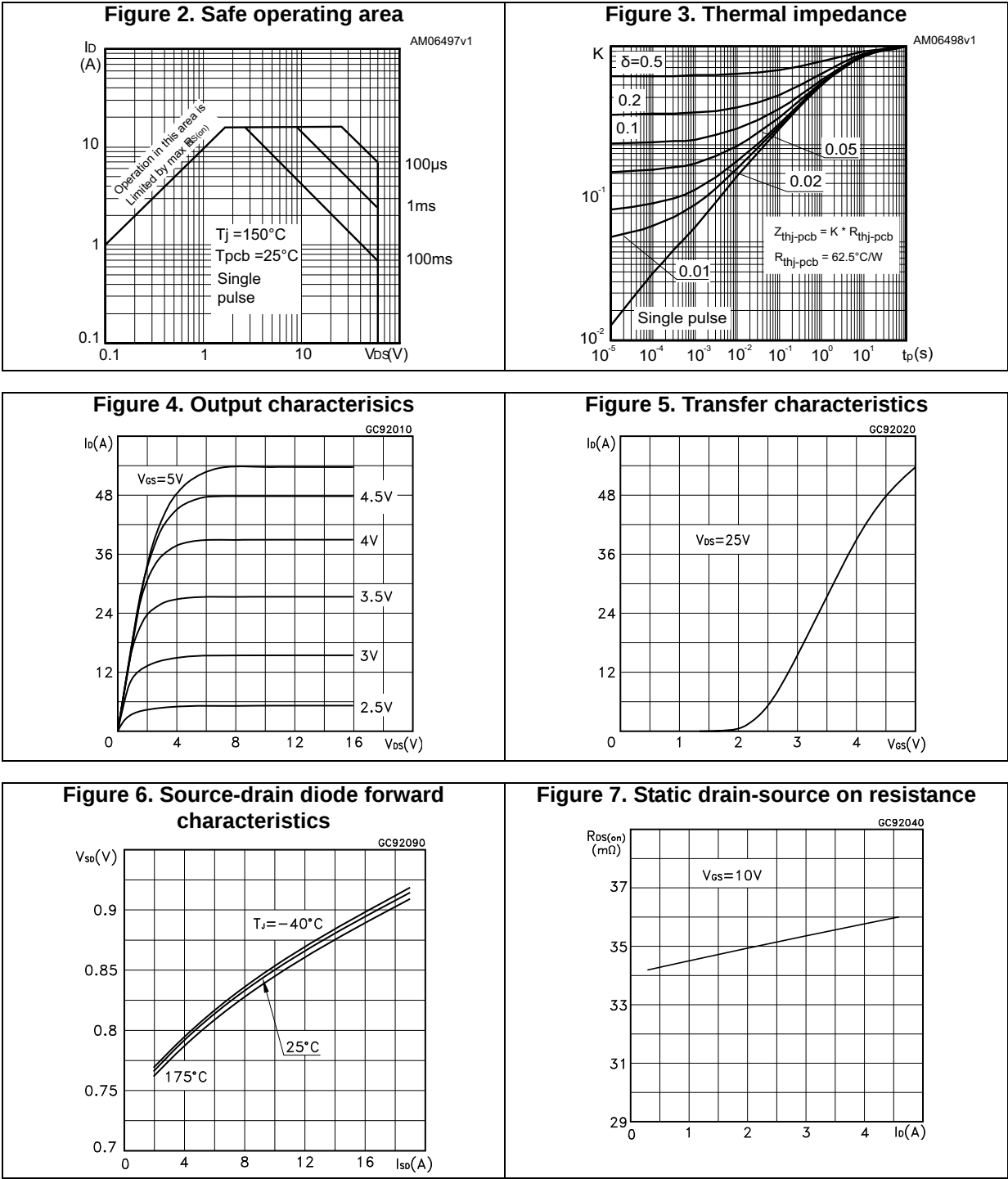


Figure 8. Gate charge vs gate-source voltage

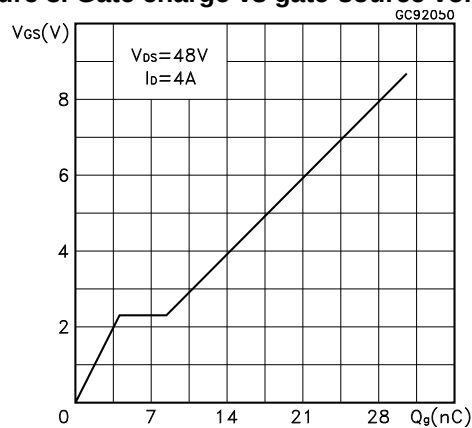


Figure 9. Capacitance variations

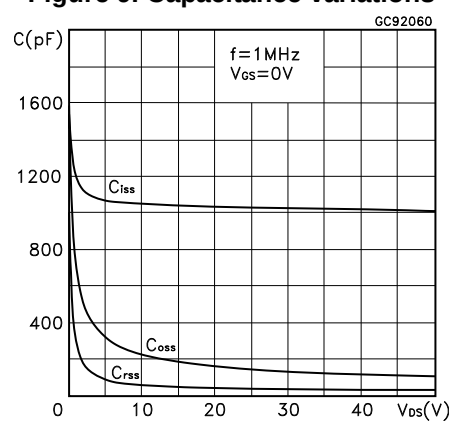


Figure 10. Normalized gate threshold voltage vs temperature

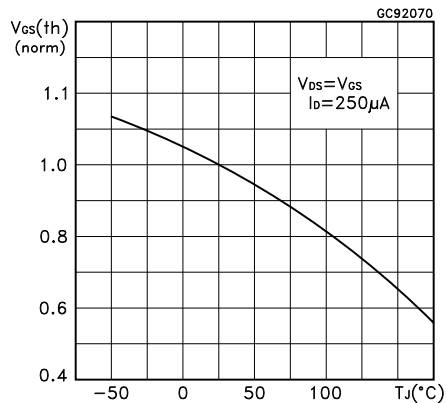
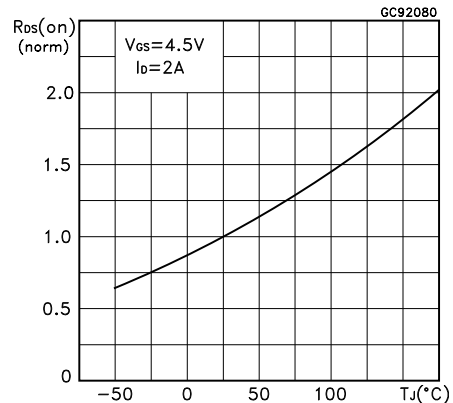
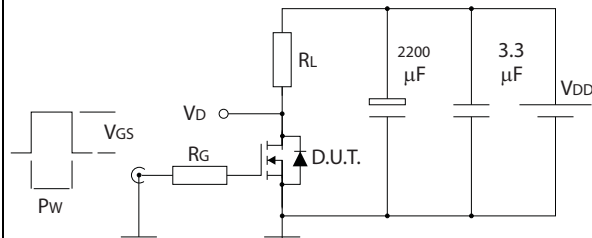


Figure 11. Normalized on resistance vs temperature



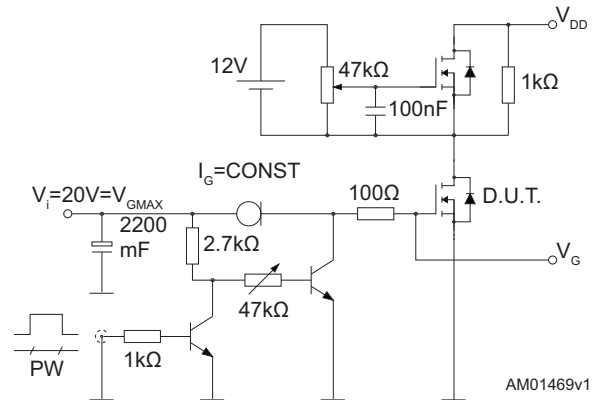
3 Test circuits

Figure 12. Switching times test circuit for resistive load



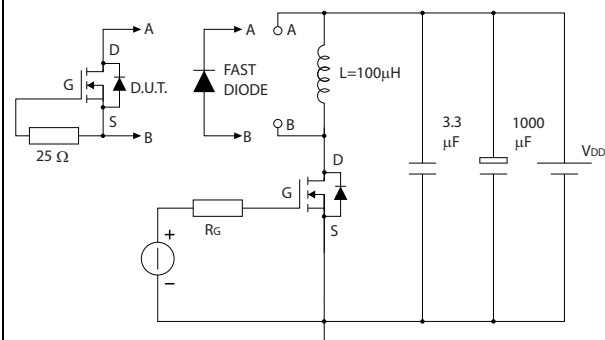
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Figure 13. Gate charge test circuit



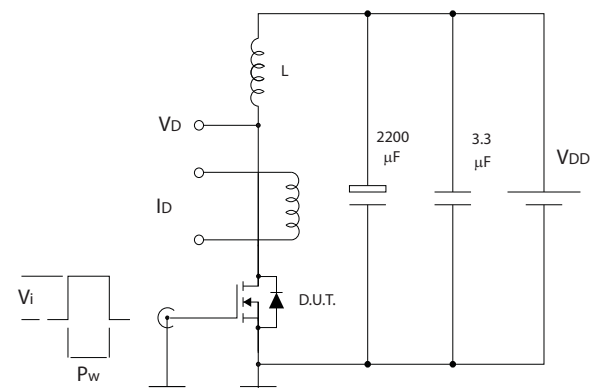
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Figure 14. Test circuit for inductive load switching and diode recovery times



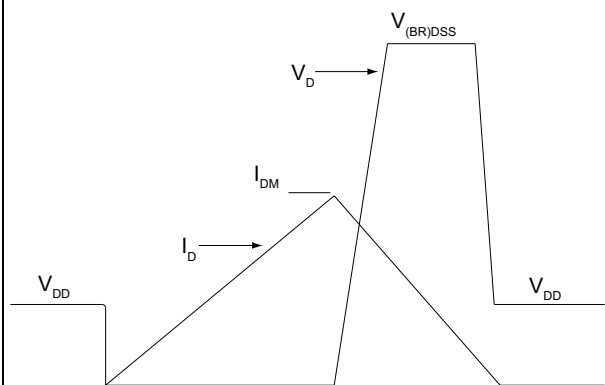
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Figure 15. Unclamped Inductive load test circuit



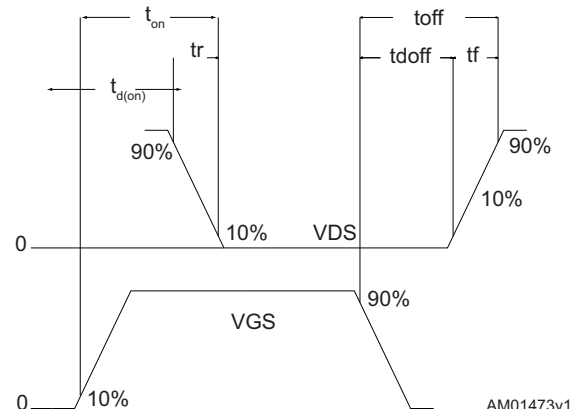
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Figure 16. Unclamped inductive waveform



AM01472v1

Figure 17. Switching time waveform



AM01473v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 SO-8 package information

Figure 18. SO-8 package outline

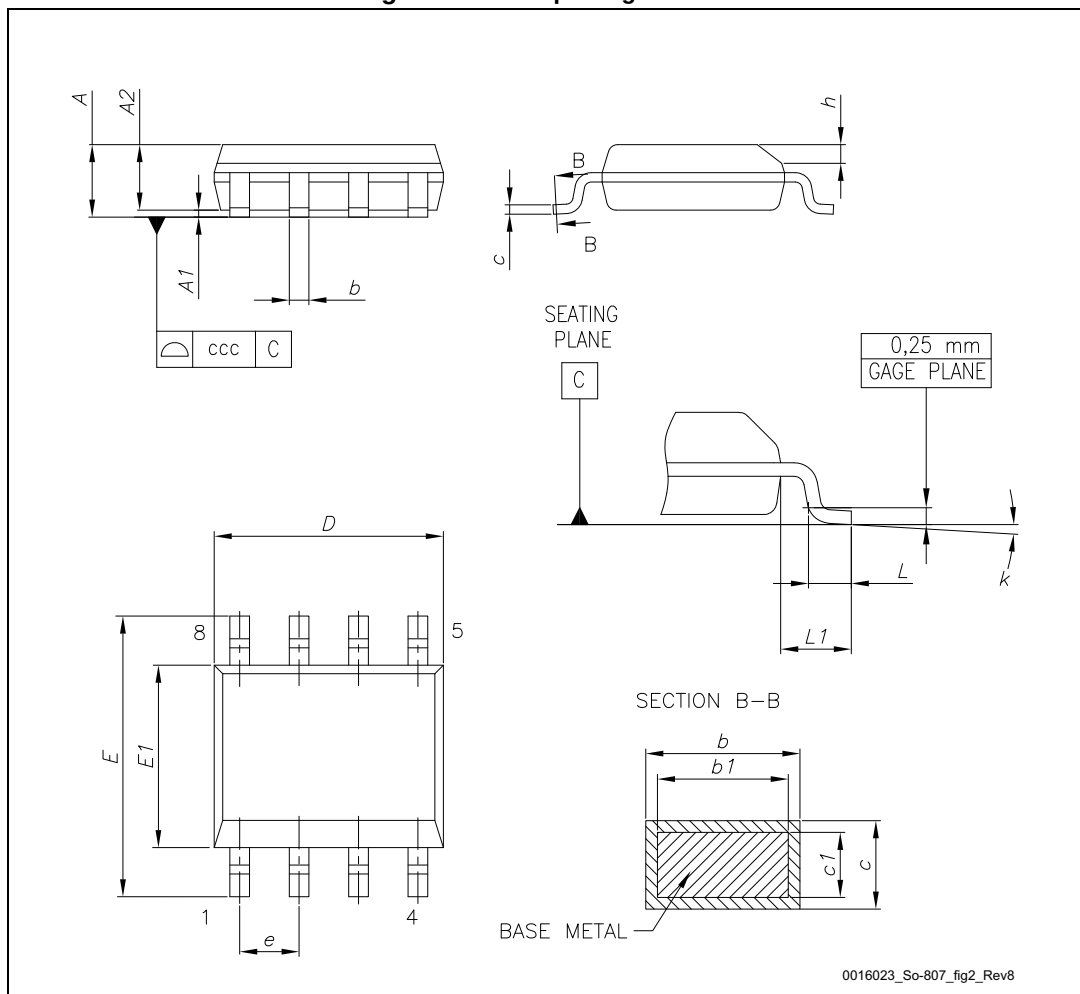
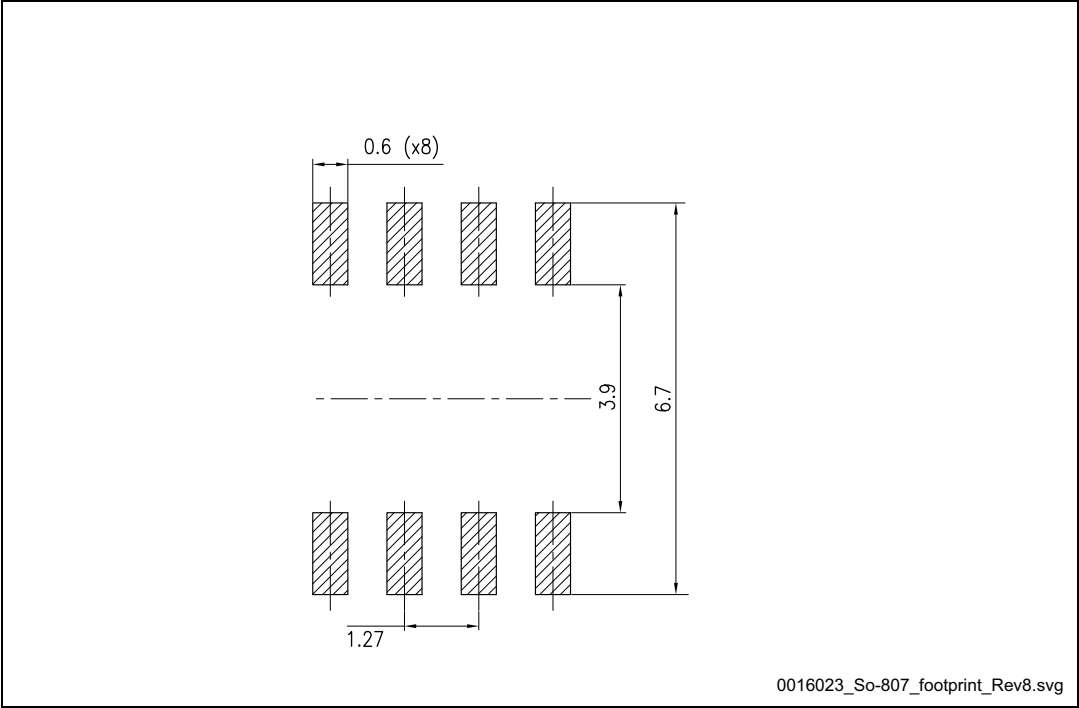


Table 8. SO-8 package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A			1.75
A1	0.10		0.25
A2	1.25		
b	0.31		0.51
b1	0.28		0.48
c	0.10		0.25
c1	0.10		0.23
D	4.80	4.90	5.00
E	5.80	6.00	6.20
E1	3.80	3.90	4.00
e		1.27	
h	0.25		0.50
L	0.40		1.27
L1		1.04	
L2		0.25	
K	0°		8°
ccc			0.10

Figure 19. SO-8 recommended footprint (dimensions are in mm)



4.2 Packing information

Figure 20. Tape and reel dimension

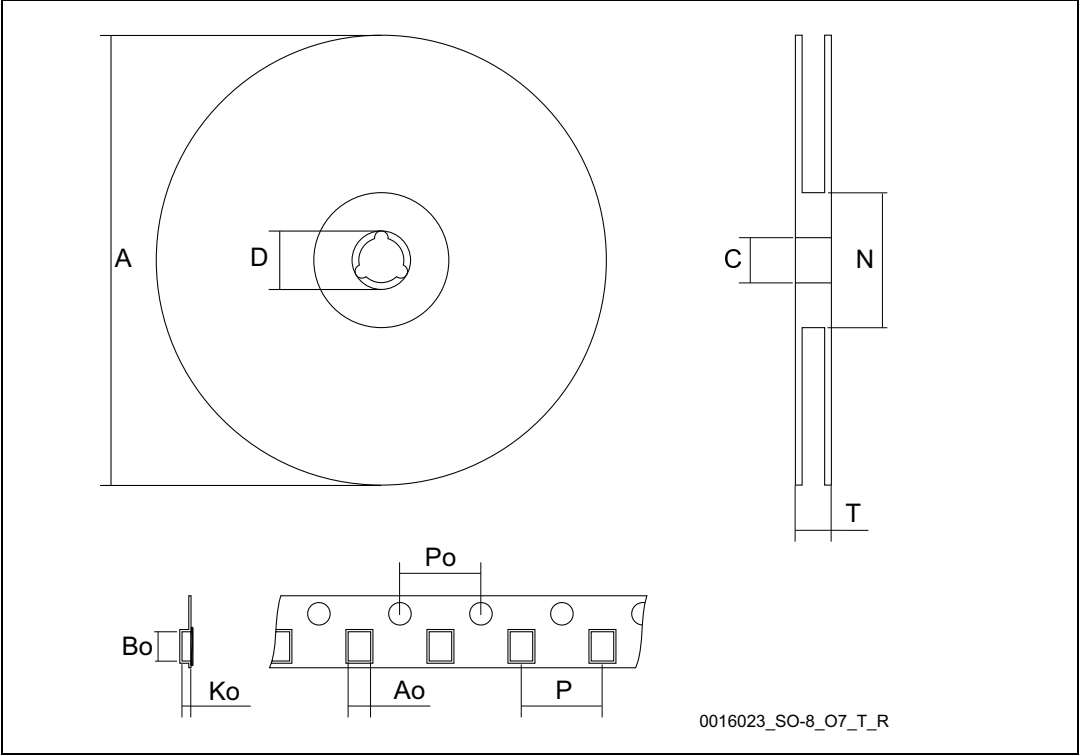


Table 9. SO-8 tape and reel mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A			330
C	12.8		13.2
D	20.2		
N	60		
T			22.4
Ao	8.1		8.5
Bo	5.5		5.9
Ko	2.1		2.3
Po	3.9		4.1
P	7.9		8.1

5 Revision history

Table 10. Revision history

Date	Revision	Changes
03-Mar-2008	1	First release
18-Mar-2010	2	<i>Figure 2: Safe operating area</i> and <i>Figure 3: Thermal impedance</i> have been changed.
17-Oct-2016	3	Updated title, features and description in cover page. Added AEC-Q101 qualified in the Features section. Updated Package information and Packing information . Minor text changes.

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